

**Search Notes**

Application/Control No.

10/785,416

Examiner

Raleigh Chiu

Applicant(s)/Patent under  
Reexamination

GORSKI ET AL.

Art Unit

3711

**SEARCHED**

Class	Subclass	Date	Examiner
473	520-524, 549	11/9/2005	RWC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR